

Search Notes

Application/Control No.

10/644,278

Examiner

TUYEN T. NGUYEN

Applicant(s)/Patent under
Reexamination

AHN, KIE

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
336	65, 83, 200, 206- 208, 232	6/11/2005	TTN
257	531	6/11/2005	TTN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR